75. Jahrestagung der DPG/DPG Frühjahrstagung, Dresden, March 13–18, 2011

Symposium

Microanalysis and Microscopy

The Microprobes (MI) division of the German Physical Society represents a platform for the discussion and the information exchange in the field of micro- and nanoanalysis of condensed matter. The broad scope of this division covers all probe methods and microscopy techniques with photons, electrons, positrons and ions to investigate the relation between structure and properties of materials. The MI group invites to a Symposium on “Microanalysis and Microscopy” during the DPG spring meeting. The Symposium is scheduled for two days, on Monday 2011-03-14 and Tuesday 2011-03-15, with invited talks, topical talks and posters. In addition, Tutorial lectures on the state of the art of X-ray microanalysis are carried out prior to the Symposium on Sunday 2011-03-13.

Topics

- EBSD and related techniques
- Kossel microdiffraction
- X-ray spectrometry
- X-ray tomography
- TEM-based material analysis
- SEM analysis
- Cathodoluminescence microscopy
- Ion beam methods
- Quantitative materials analysis at the micro or nanoscale
- Progress of microprobe instrumentation and methods

Abstract submission

online at www.dpg-tagung.de/ddll/submission.html
(go in the input field to MI: Microprobes division)
Deadline: **December 10, 2010**

See as well: www.dpg-physik.de/dpg/gliederung/fv/mi/index.html

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Invited tutorials and lectures:

Stefan Langner (Bruker AXS Berlin):
Tutorial on Energy dispersive X-ray spectroscopy – from the method to the instrumentation, *requested*

Frank Bauer (Oxford Instruments Wiesbaden): Tutorial on WDS technique, *requested*

Christian Schroer (TU Dresden): Tutorial on Hard X-Ray scanning microscopy and tomography with elemental, chemical, and structural contrast

Tilman Butz (Universität Leipzig): Tutorial on Particle-induced X-ray emission, Rutherford backscattering, scanning ion microscopy and tomography

Stefan Zaefferer (MPI für Eisenforschung Düsseldorf):
Diffraction techniques in the scanning electron microscope: making SEM a universal tool for microstructure research

Günter Zschornack (Forschungszentrum Dresden-Rossendorf/TU Dresden):
X-ray spectroscopy with highly charged ions

Wolfgang Jäger (Christian-Albrechts-Universität zu Kiel):
STEM investigations of nanomaterials

Heiner Jaksch (Zeiss NTS Oberkochen):
High resolution backscattered electron imaging, *requested*